

SEMITRANS<sup>TM</sup> 3

### **IGBT** Modules

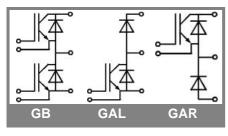
SKM 150GB123D SKM 150GAL123D SKM 150GAR123D

#### Features

- MOS input (voltage controlled)
- N channel, Homogeneous Si
- Low inductance case
- Very low tail current with low temperature dependence
- High short circuit capability, self limiting to 6 x I<sub>cnom</sub>
- Latch-up free
- Fast & soft inverse CAL diodes
- Isolated copper baseplate using DCB Direct Copper Bonding
- Large clearance (12 mm) and creepage distances (20 mm)

#### **Typical Applications**

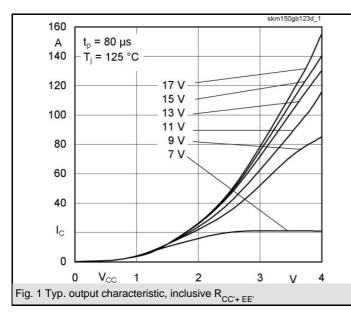
• Switching (not for linear use)

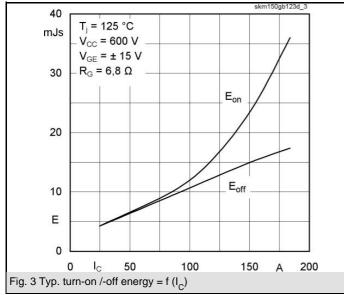


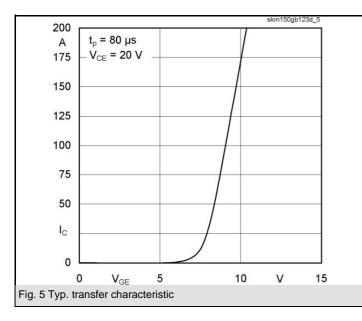
	Absolute Maximum Ratings $T_c = 25 \text{ °C}$ , unless otherwise spec						
	Symbol	Conditions	Values	Units			
	IGBT						
	V <sub>CES</sub>		1200	V			
	I <sub>C</sub>	T <sub>c</sub> = 25 (80) °C	150 (110)	А			
	I <sub>CRM</sub>	t <sub>p</sub> = 1 ms	200	A			
	V <sub>GES</sub>		± 20	V			
	T <sub>vj</sub> , (T <sub>stg</sub> )	$T_{OPERATION} \le T_{stg}$	- 40 + 150 (125)	°C			
	V <sub>isol</sub>	AC, 1 min.	2500	V			
	I <sub>F</sub>	T <sub>c</sub> = 25 (80) °C	150 (100)	А			
	I <sub>FRM</sub>	t <sub>p</sub> = 1 ms	200	А			
	I <sub>FSM</sub>	t <sub>p</sub> = 10 ms; sin.; T <sub>j</sub> = 150 °C	1100	А			
	Freewheeling diode						
	I <sub>F</sub>	T <sub>c</sub> = 25 (80) °C	200 (135)	А			
	I <sub>FRM</sub>	t <sub>p</sub> = 1 ms	300	А			
	I <sub>FSM</sub>	t <sub>p</sub> = 10 ms; sin.; T <sub>j</sub> = 150 °C	1450	А			

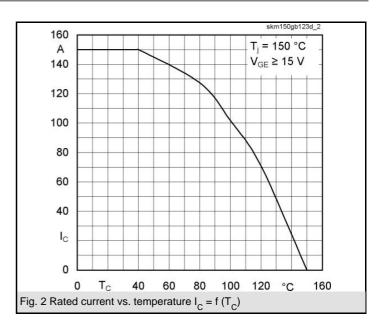
Characteristics		$T_c = 25 \text{ °C}$ , unless otherwise specified			
Symbol	Conditions	min.	typ.	max.	Units
IGBT					
V <sub>GE(th)</sub>	$V_{GE} = V_{CE}, I_C = 4 \text{ mA}$	4,5	5,5	6,5	V
ICES	$V_{GE} = 0, V_{CE} = V_{CES}, T_j = 25 (125) °C$		0,1	0,3	mA
V <sub>CE(TO)</sub>	$T_j = 25 (125) °C$		1,4 (1,6)	1,6 (1,8)	V
r <sub>CE</sub>	$V_{GE} = 15 \text{ V}, \text{ T}_{j} = 25 (125) \text{ °C}$		11 (15)	14 (19)	mΩ
V <sub>CE(sat)</sub>	$I_{Cnom} = 100 \text{ A}, V_{GE} = 15 \text{ V}, \text{ chip level}$		2,5 (3,1)	3 (3,7)	V
C <sub>ies</sub>	under following conditions		6,5	8,5	nF
C <sub>oes</sub>	V <sub>GE</sub> = 0, V <sub>CE</sub> = 25 V, f = 1 MHz		1	1,5	nF nF
C <sub>res</sub>			0,5	0,6 20	nF
	real terminal ship $T = 25 (125) \circ C$		0.25 (0.5)	20	
R <sub>CC'+EE'</sub>	res., terminal-chip $T_c = 25 (125) \degree C$		0,35 (0,5)		mΩ
t <sub>d(on)</sub>	$V_{CC} = 600 \text{ V}, \text{ I}_{Cnom} = 100 \text{ A}$		160	320	ns
t <sub>r</sub>	$R_{Gon} = R_{Goff} = 6,8 \Omega, T_j = 125 °C$		80 400	160 520	ns ns
t <sub>d(off)</sub> t	V <sub>GE</sub> = ± 15 V		400 70	100	ns
τ <sub>f</sub> Ε (Ε )				100	mJ
E <sub>on</sub> (E <sub>off</sub> )			13 (11)		ШJ
Inverse d		i		<u> </u>	1
V <sub>F</sub> = V <sub>EC</sub>	I <sub>Enom</sub> = 100 A; V <sub>GE</sub> = 0 V; T <sub>j</sub> = 25 (125)		2 (1,8)	2,5	V
V <sub>(TO)</sub>	T <sub>i</sub> = 125 () °C			1,2	V
r <sub>T</sub>	$T_{j} = 125$ () °C		8	11	mΩ
I <sub>RRM</sub>	I <sub>Fnom</sub> = 100 A; T <sub>j</sub> = 25 ( 125 ) °C		35 (50)		Α
Q <sub>rr</sub>	di/dt = 1000 A/µs		5 (14)		μC
E <sub>rr</sub>	V <sub>GE</sub> = V				mJ
FWD					
$V_F = V_{EC}$	I <sub>F</sub> = 150 A; V <sub>GE</sub> = 0 V, T <sub>j</sub> = 25 (125) °C		2 (1,8)	2,5	V
V <sub>(TO)</sub>	$T_{j} = 125$ () °C		_	1,2	V
r <sub>T</sub>	$T_j = 125$ () °C		5	8,7	mΩ
I <sub>RRM</sub>	$I_{F} = 100 \text{ A}; T_{j} = 25 (125) ^{\circ}\text{C}$		40 (65)		A
Q <sub>rr</sub>	di/dt = A/µs		5 (15)		μC
E <sub>rr</sub>	V <sub>GE</sub> = V				mJ
	characteristics				1
R <sub>th(j-c)</sub>	per IGBT			0,15	K/W
R <sub>th(j-c)D</sub>	per Inverse Diode			0,3	K/W
R <sub>th(j-c)FD</sub>	per FWD			0,25	K/W
R <sub>th(c-s)</sub>	per module			0,038	K/W
Mechanic	cal data				
M <sub>s</sub>	to heatsink M6	3		5	Nm
M <sub>t</sub>	to terminals M6	2,5		5	Nm
w				325	g

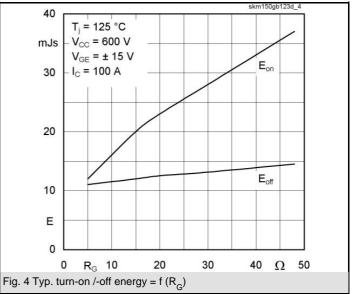
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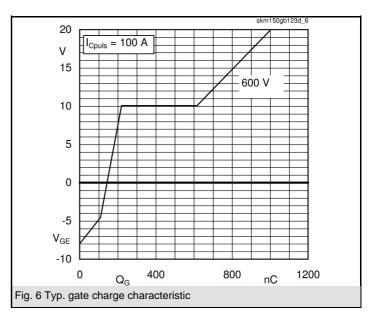


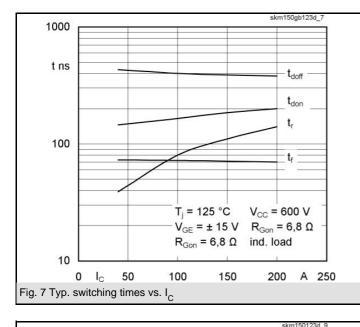


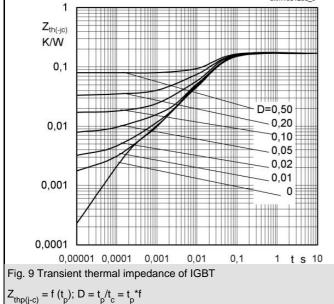


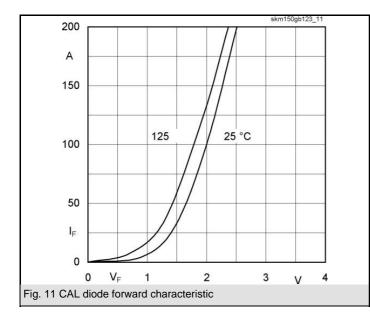


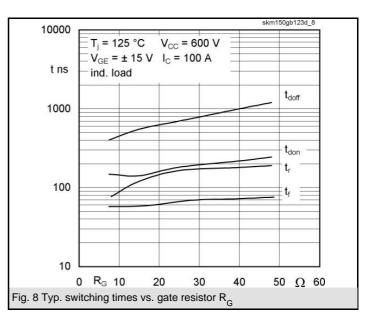


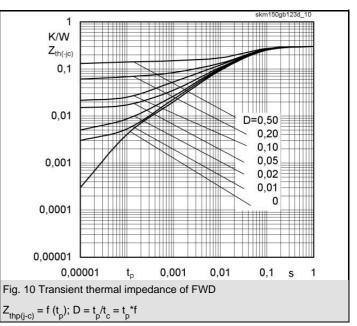


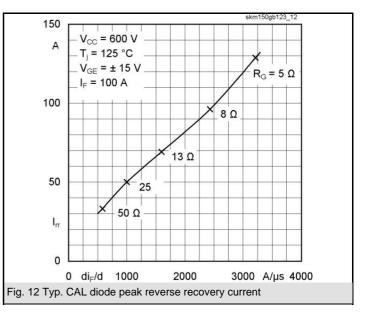


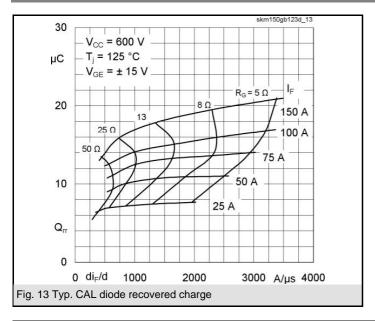


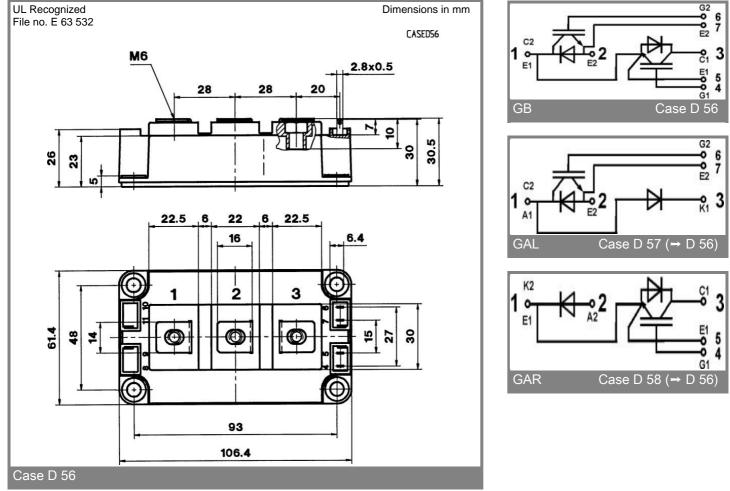












This is an electrostatic discharge sensitive device (ESDS), international standard IEC 60747-1, Chapter IX.

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